

## Editorial

### Special issue: IMEKO Technical Committee 21 (Part II)

Dear Reader,

The Technical Committee 21 (TC21) of the International Measurement Confederation (IMEKO) completes its 2012 collaboration with the *International Journal of Metrology and Quality Engineering* with this second Special issue. It will continue in 2013.

Also this second issue is based on the activities of members and friends, and is partially originating from presentations at the XX IMEKO World Congress, held in Busan, Korea in September 2012. Everybody is invited to join our activities.

The main event of this Committee, whose website is at <http://joomla.imeko.org/index.php/tc21-homepage>, is the International Conference “Advanced Mathematical and Computational Tools in Metrology” (AMCTM), also providing input for the book Series with the same name, published by TC21 with World Scientific Publ. Co., Singapore (for the last book, the 9th in this Series, see <http://www.worldscientific.com/worldscibooks/10.1142/8432>).

Franco Pavese, TC21 Chairman

Alistair B. Forbes, TC21 Scientific Secretary

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